

Cont. A1
arc face, a radius of curvature thereof is determined to be equal to or larger than 0.9 mm and an angle of an opening extended linearly from the bottom portion and opened at the side face of the wafer is 90 degree. Further, also an end edge of the opening is chamfered by [R] 0.9 mm and accordingly, a linear portion except the circular arc face portion of the bottom portion of the notch 1 becomes 0.669 mm at maximum. --

IN THE CLAIMS:

Please replace Claims 1-5 with the following rewritten claims:

Sub C1
-- 1. A semiconductor wafer with a dot mark having a maximum length of 1 to 13 μm on an inner wall face of a notch formed on an outer peripheral face thereof. --

Sub D2
A2
-- 2. The semiconductor wafer according to Claim 1, wherein upper and lower edge line portions of the inner wall face of the notch are respectively chamfered to thereby constitute upper and lower inclined faces and the dot mark is formed on the inclined faces. --

Sub D3
-- 3. The semiconductor wafer according to Claim 2, wherein an angle of an inclination of at least one inclined face relative to the surface of the semiconductor wafer is equal to or smaller than 30 degrees. --

-- 4. The semiconductor wafer according to Claim 2, wherein a surface roughness of at least one inclined face is equal to or smaller than $1\text{ }\mu\text{m}$. --

cont.
A2 sub C2 -- 5. The semiconductor wafer according to Claim 2, wherein the dot mark is formed on either one of the upper and lower inclined faces. --

Please add the following new claims:

Sub D5 -- 6. The semiconductor wafer according to Claim 5, wherein an angle of an inclination of the inclined face relative to the surface of the semiconductor wafer is equal to or smaller than 30 degrees. --

-- 7. The semiconductor wafer according to Claim 5, wherein a surface roughness of the inclined face is equal to or smaller than $1\text{ }\mu\text{m}$. --

A3 sub C3 -- 8. The semiconductor wafer according to Claim 1, wherein the dot mark is formed by irradiating a laser beam. --

sub B2 -- 9. The semiconductor wafer according to Claim 1, wherein a dot mark has a height in the range of 0.005 to $5\text{ }\mu\text{m}$. --